

# P211 L-EFT

Current Generator up to 5 V Langer Pulse 1.5/5 ns



## Short description

The probe is used to couple conducted pulse current into the test IC. It simulates attenuated disturbance current pulses at the IC input, which occur at tests according to IEC 61000-4-2 / ICE 61000-4-4. These disturbance current pulses can occur above the magnetic fields during a test.

If the magnetic field couples into a low-ohm conductor loop at an IC pin of a test IC, a voltage will be induced. This voltage drives a disturbance current pulse into the IC pin and can lead to interferences.

The coupling behaviour can be simulated by a low-ohm pulse voltage source. Therefore the P211 has a low internal resistance. The pulse voltage is adjustable in the range  $\pm$  (0.5 - 5) V.

The probe is operated by the BPS 201 burst power station and the BPS-Client control software.

The measuring station of the test IC needs the ICE1 test environment. Depending on the measuring task additional equipment is required (Oscilloscope, PC).

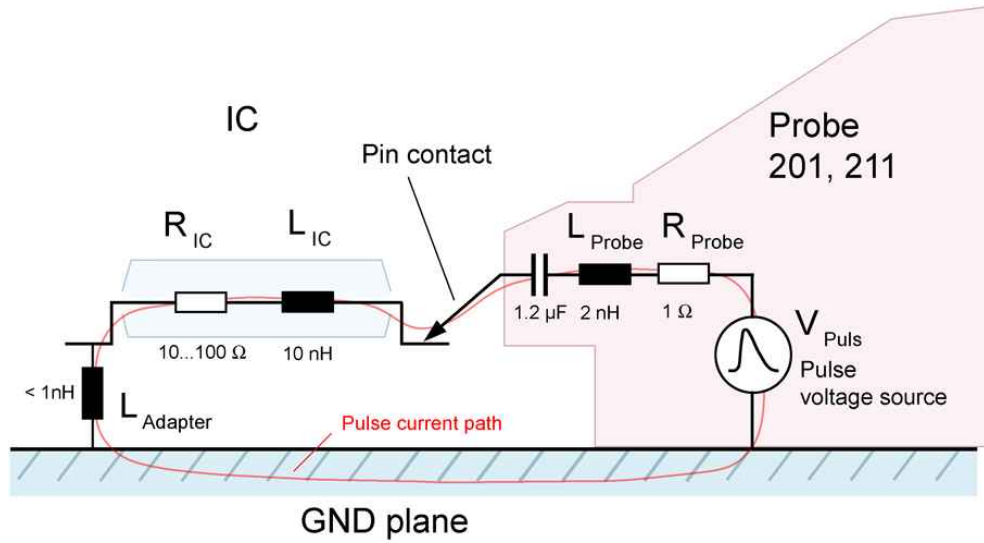
## Technical parameters

<b>Internal resistance</b>	$\approx 1 \Omega$
<b>Coupling capacity</b>	1.2 $\mu$ F
<b>Pulse parameter</b>	
Shape	1.5 / 5 ns
Frequency	0.1 Hz - 20 kHz
Voltage	$\pm$ (0.5 - 5) V
<b>Inductance</b>	$\approx 2$ nH
<b>Sizes (L x W x H)</b>	(78 x 35 x 31) mm

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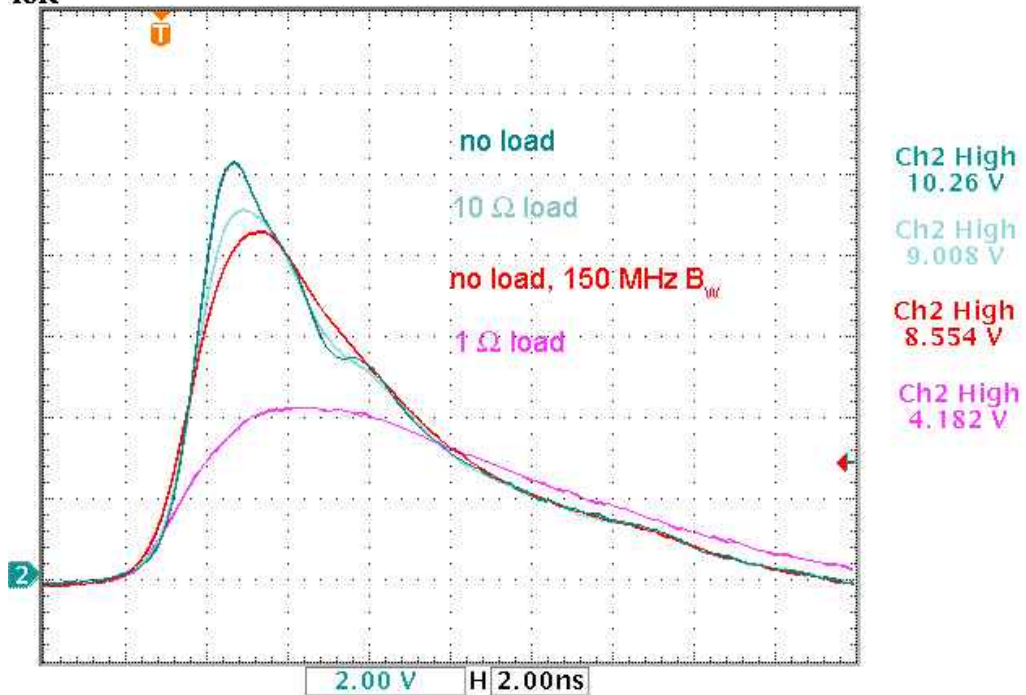
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Equivalent circuit



Pulse shape (measured)

Tek

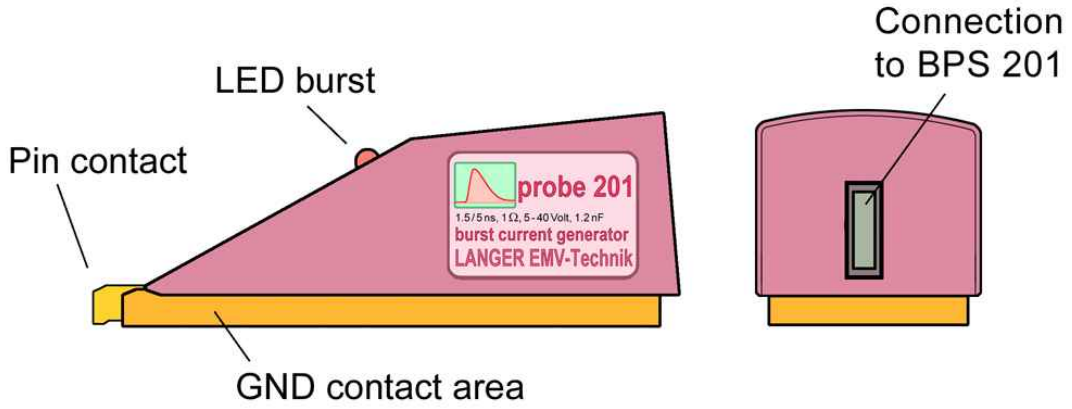


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Design, view 1



Measurement set up

